

32M-Bit (4M X 8/2M X 16) CMOS MASK ROM

FEATURES

- Switchable organization
4,194,304 x8(byte mode)
2,097,152 x16(word mode)
- Fast access time : 120ns (Max.)
- Supply voltage : single +5V
- Current consumption
Operating : 60 mA(max.)
Standby : 50 μ A (max.)
- Fully static operation
- All inputs and outputs TTL compatible
- Three state outputs
- Polarity programmable chip enable and output enable pin
- Package
- KM23C32000AG : 44-SOP-600

GENERAL DESCRIPTION

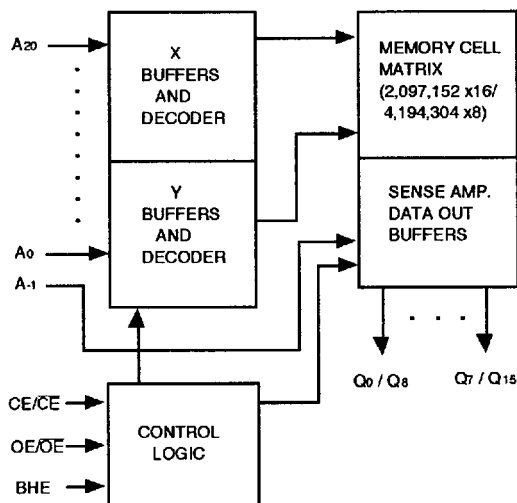
The KM23C32000AG is a fully static mask programmable ROM fabricated using silicon gate CMOS process technology, and is organized either as 4,194,304x8bit(byte mode) or as 2,097,152x16bit(word mode) depending on BHE voltage level.(See mode selection table)

This device operates with a 5V single power supply, and all inputs and outputs are TTL compatible. Because of its asynchronous operation, it requires no external clock assuring extremely easy operation.

It is suitable for use in program memory of micro-processor, and data memory, character generator.

The KM23C32000AG is packaged in a 44-SOP and provides polarity programmable CE and OE buffer as user option mode.

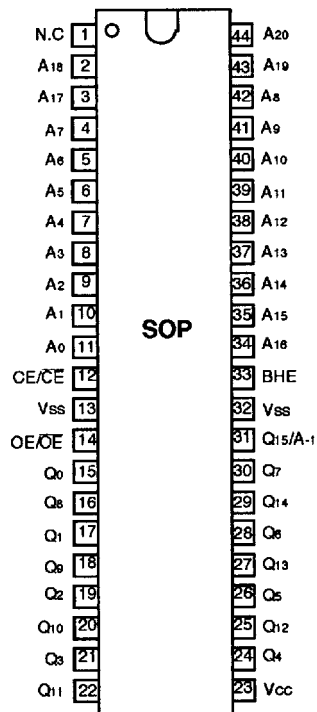
FUNCTIONAL BLOCK DIAGRAM



| Pin Name | Pin Function |
|----------|--|
| A0-A20 | Address Inputs |
| Q0-Q14 | Data Outputs |
| Q15/A-1 | Output 15(Word mode)/ LSB Address (Byte mode) |
| BHE | Word/Byte Selection |
| CE/CE* | Chip Enable |
| OE/OE* | Output Enable |
| Vcc | Power (+5V) |
| Vss | Ground |
| N.C | No Connection |

* User Selectable Polarity

PIN CONFIGURATION



KM23C32000AG

ABSOLUTE MAXIMUM RATINGS

| Item | Symbol | Rating | Unit |
|------------------------------------|-------------------|--------------|------|
| Voltage on Any Pin Relative to Vss | V _{IN} | -0.3 to +7.0 | V |
| Temperature Under Bias | T _{bias} | -10 to +85 | °C |
| Storage Temperature | T _{stg} | -55 to +150 | °C |

* Permanent device damage may occur if "ABSOLUTE MAXIMUM RATINGS" are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS (Voltage reference to Vss, T_A=0 to 70°C)

| Item | Symbol | Min | Typ | Max | Unit |
|----------------|-----------------|-----|-----|-----|------|
| Supply Voltage | V _{CC} | 4.5 | 5.0 | 5.5 | V |
| Supply Voltage | V _{SS} | 0 | 0 | 0 | V |

DC CHARACTERISTICS

| Parameter | Symbol | Test Conditions | Min | Max | Unit |
|--------------------------------|------------------|---|------|----------------------|------|
| Operating Current | I _{CC} | $\overline{CE}=\overline{OE}=V_{IL}$, f=6.7MHz all outputs open | - | 60 | mA |
| Standby Current (TTL) | I _{SB1} | $\overline{CE}=V_{IH}$, all outputs open | - | 1 | mA |
| Standby Current (CMOS) | I _{SB2} | $\overline{CE}=V_{CC}$, all outputs open | - | 50 | μA |
| Input Leakage Current | I _I | V _{IN} =0 to V _{CC} | - | 10 | μA |
| Output Leakage Current | I _{LO} | V _{OUT} =0 to V _{CC} | - | 10 | μA |
| Input High Voltage, All Inputs | V _{IH} | | 2.2 | V _{CC} +0.3 | V |
| Input Low Voltage, All Inputs | V _{IL} | | -0.3 | 0.8 | V |
| Output High Voltage Level | V _{OH} | I _{OH} = - 400 μA | 2.4 | - | V |
| Output Low Voltage Level | V _{OL} | I _{OL} = 2.1 mA | - | 0.4 | V |

CAPACITANCE (T_A=25°C, f=1.0MHz)

| Item | Symbol | Test Conditions | Min | Max | Unit |
|--------------------|------------------|-----------------------|-----|-----|------|
| Output Capacitance | C _{OUT} | V _{OUT} = 0V | - | 12 | pF |
| Input Capacitance | C _{IN} | V _{IN} = 0V | - | 12 | pF |

Note : Capacitance is periodically sampled and not 100% tested.

MODE SELECTION

| CE/ \overline{CE} | OE/ \overline{OE} | BHE | Q15/A-1 | Mode | Data | Power |
|---------------------|---------------------|-----|---------|-----------|---|---------|
| L/H | X | X | X | Standby | High-Z | Standby |
| H/L | L/H | X | X | Operating | High-Z | Active |
| H/L | H/L | H | Output | Operating | Q ₀ -Q ₁₅ :Dout | Active |
| | | L | Input | Operating | Q ₀ -Q ₇ :Dout Q ₈ -Q ₁₄ :High-Z | Active |

AC CHARACTERISTICS ($T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted.)

TEST CONDITIONS

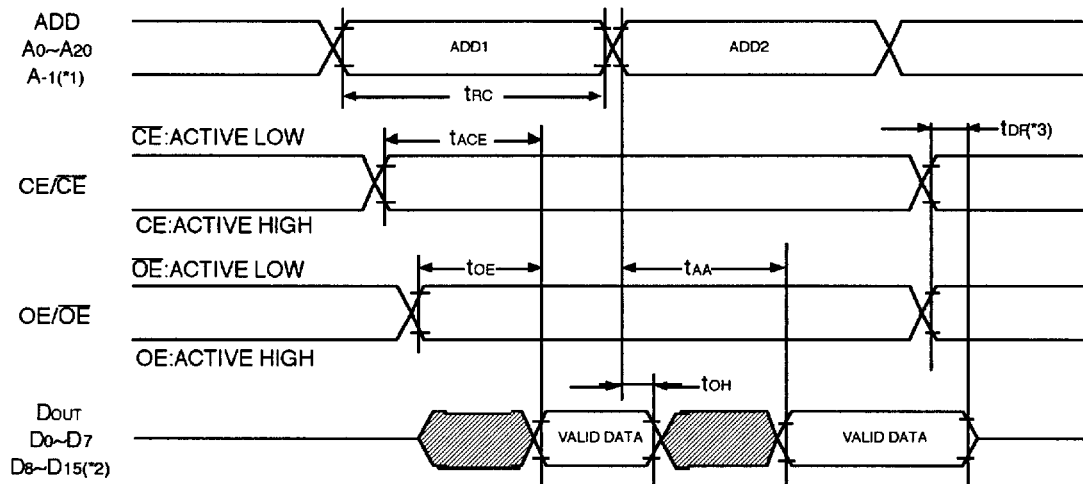
| Item | Value |
|--------------------------------|-------------------------------------|
| Input Pulse Levels | 0.6V to 2.4V |
| Input Rise and Fall Times | 10ns |
| Input and Output timing Levels | 0.8V and 2.0V |
| Output Loads | 1 TTL Gate and $C_L = 100\text{pF}$ |

READ CYCLE

| Parameter | Symbol | KM23C32000AG-12 | | KM23C32000AG-15 | | KM23C32000AG-20 | | Unit |
|---|------------------|-----------------|-----|-----------------|-----|-----------------|-----|------|
| | | Min | Max | Min | Max | Min | Max | |
| Read Cycle Time | t _{RC} | 120 | | 150 | | 200 | | ns |
| Chip Enable Access Time | t _{ACE} | | 120 | | 150 | | 200 | ns |
| Address Access Time | t _{AA} | | 120 | | 150 | | 200 | ns |
| Output Enable Access Time | t _{OE} | | 60 | | 70 | | 90 | ns |
| Output or Chip Disable to Output High-Z | t _{DF} | | 20 | | 30 | | 40 | ns |
| Output Hold from Address Change | t _{OH} | 0 | | 0 | | 0 | | ns |

TIMING DIAGRAM

READ



(*1) Byte Mode only. A-1 is Least Significant Bit Address. (BHE= V_{IL})

(*2) Word Mode only. (BHE= V_{IH})

(*3) t_{DF} is defined as the time which the outputs achieve the open circuit condition and is not referenced to V_{OH} or V_{OL} level.

PACKAGE DIMENSIONS

44 LEAD SMALL OUTLINE PACKAGE

Unit : mm/Inch

